



WANSEMI
万晶半导体

WX012CN09LL

N-channel Enhancement Mode Power MOSFET

TOLL/90V/ $\pm 20V$ /2.9V/325A/1.3m Ω

Rev0.5



90V, 1.3mΩ, 325A, N-channel MOSFET

1. Features

- ◆ Excellent RDS(ON) and Low Gate Charge
- ◆ 100% UIS Tested
- ◆ 100% ΔVds Tested
- ◆ Halogen-free; RoHS-compliant

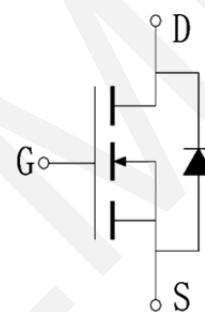
V _{DS}	R _{DS(on)} Typ.	I _D Max.
90V	1.3mΩ @10V	325A

2. Applications

- ◆ Load Switch
- ◆ PWM Application
- ◆ Power Management



TOLL
Pin Description



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Package	Marking	PCS/Reel	PCS/CTN.
WX012CN09LL	TOLL	012N09	2,000	16,000

4. Absolute Max Ratings at Ta=25°C (Note1)

Parameter		Symbol	Maximum	Units
Drain to Source Voltage		V _{DSS}	90	V
Gate to Source Voltage		V _{GSS}	±20	V
Drain Current (DC)	T C = 25°C	I _D	325	A
	T C = 100°C	I _D	205	A
Drain Current (Pulse), PW≤300μs		I _{DM}	1300	A
Avalanche Energy, Single Pulsed		E _{AS}	1823	mJ
Total Dissipation	T C = 25°C	P _D	313	W
	T C = 100°C	P _D	125	W
Junction Temperature		T _j	150	°C
Storage Temperature		T _{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may



be affected.

5.Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Junction to Ambient	R _{θJA}	35	°C/W
Junction to case	R _{θJC}	0.2	°C/W

Note 2: When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.

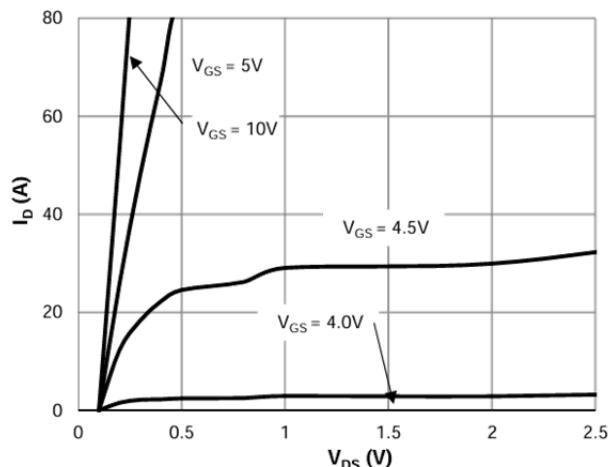
6.Electrical Characteristics at Ta=25°C (Note 2)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	I _D = 250μA, V _{GS} = 0V	90	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = 90V, V _{GS} = 0V	-	-	1	μA
Gate to Source Leakage Current	I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V	-	-	±99	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	2.6	2.9	3.3	V
Static Drain to Source On-State Resistance	R _{DS(on)}	I _D =20A, V _{GS} =10V	-	1.3	2.4	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =45V, Frequency=1.0MHz	-	12625	-	pF
Output Capacitance	C _{oss}		-	2099	-	pF
Reverse Transfer Capacitance	C _{rss}		-	269	-	pF
Turn-on Delay Time	t _{d(on)}	V _{DS} = 20V, R _L =1.0Ω V _{GS} = 10V, R _{GEN} =3.0Ω	-	40	-	ns
Rise Time	t _r		-	67	-	ns
Turn-off Delay Time	t _{d(off)}		-	131	-	ns
Fall Time	t _f		-	91	-	ns
Total Gate Charge	Q _g	V _{DS} = 20V, V _{GS} = 0 to 10V, I _D =20A	-	230	-	nC
	Q _{gs}		-	56	-	nC
	Q _{gd}		-	76	-	nC
Diode Forward Voltage	V _{FSD}	I _S = 20A, V _{GS} = 0	0.5	-	1.2	V

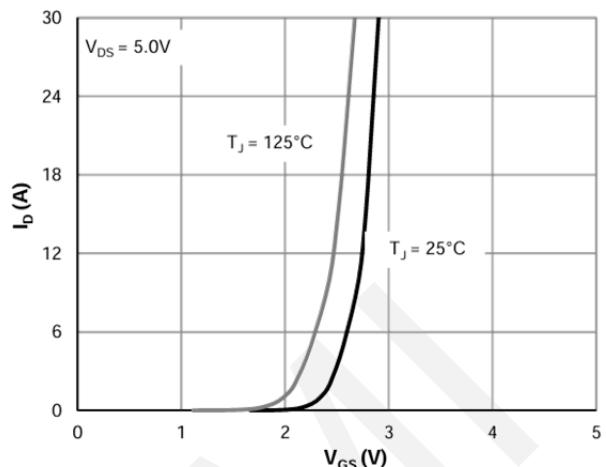
Note 2: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



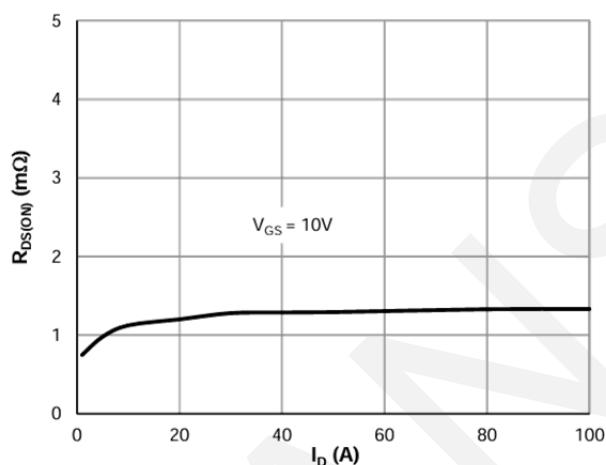
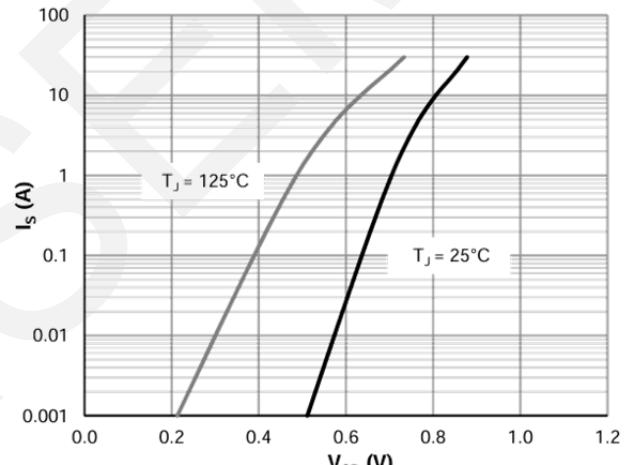
7.Typical electrical and thermal characteristics



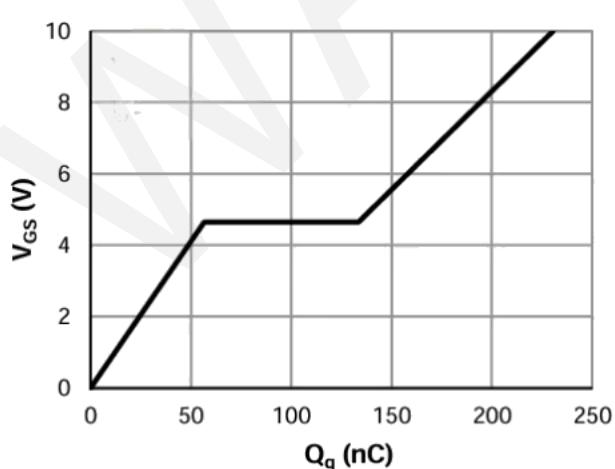
Saturation Characteristics



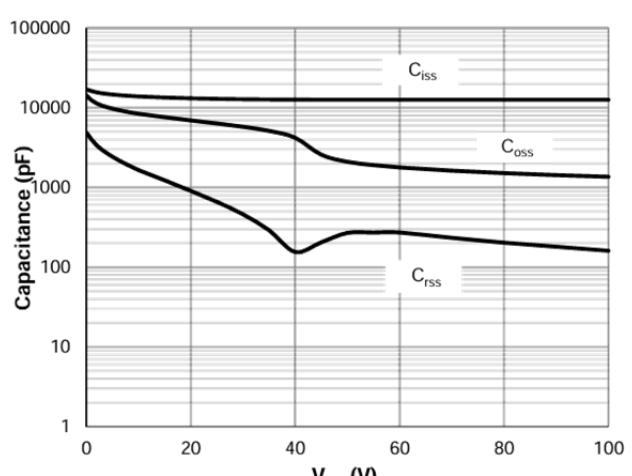
Transfer Characteristics

 $R_{DS(on)}$ vs.Drain Current

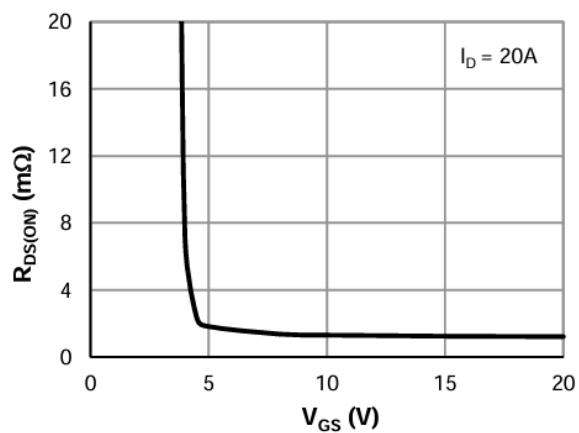
Body-Diode Characteristics



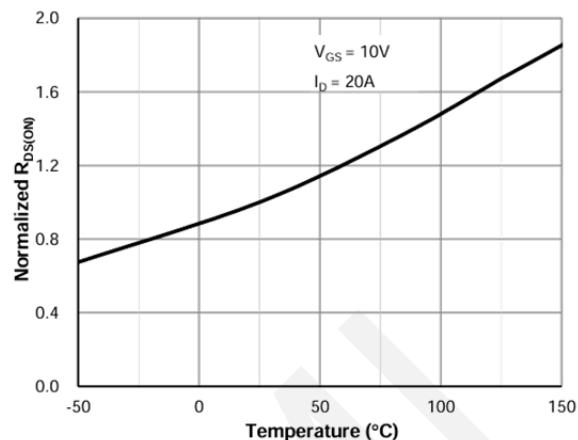
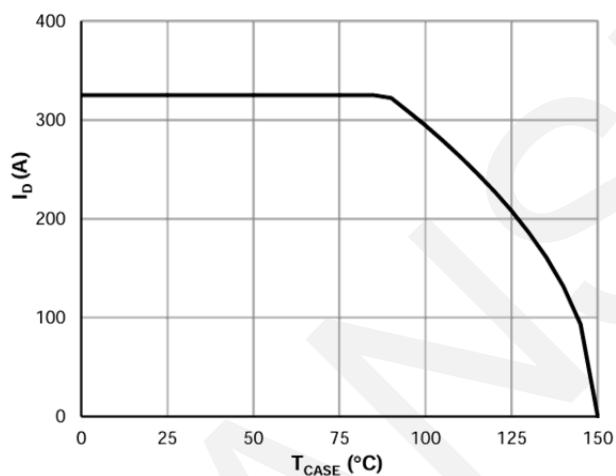
Gate Charge Characteristics



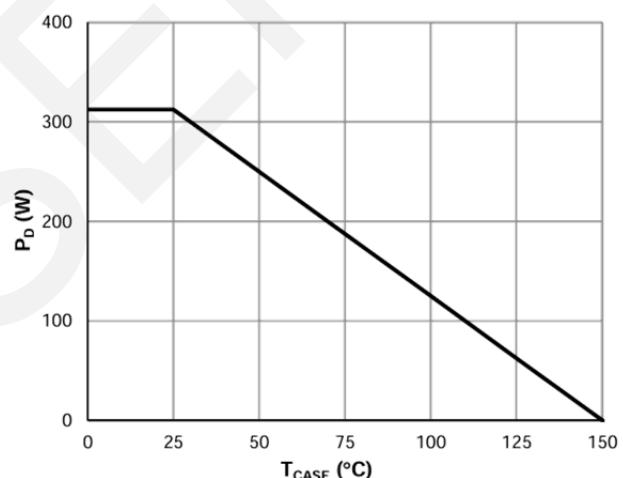
Capacitance Characteristics



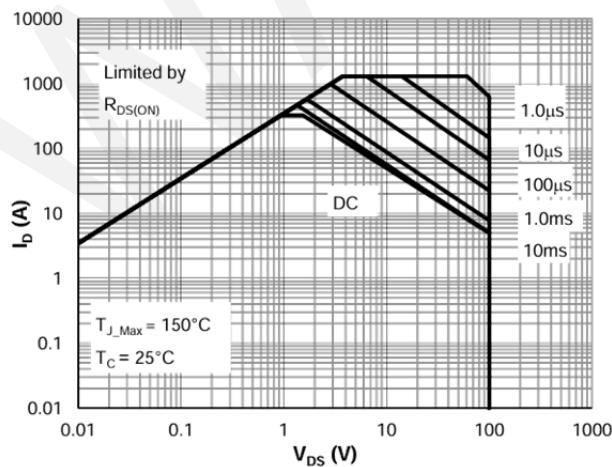
R DS(ON) vs. V GS

Normalized on Resistance vs.
Junction Temperature

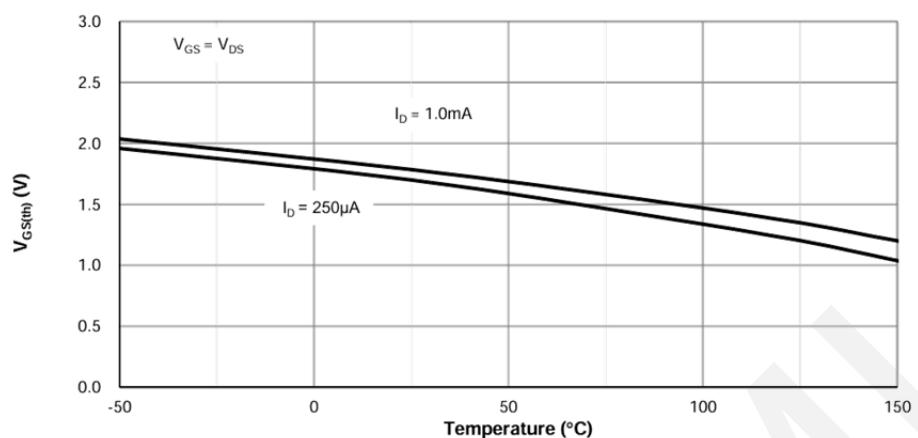
Power De-rating



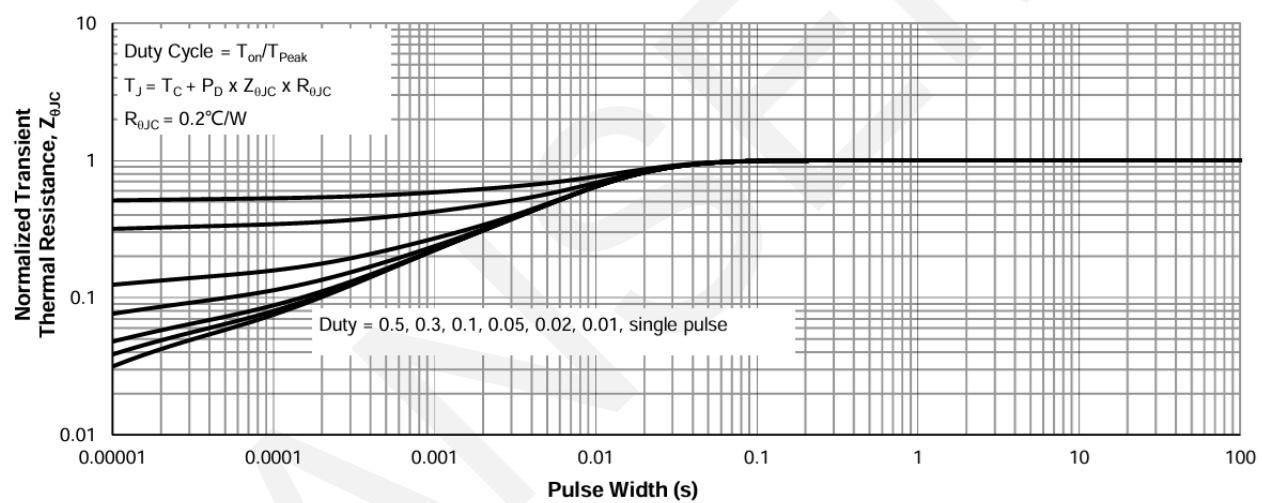
Current De-rating



Maximum Safe Operating Area



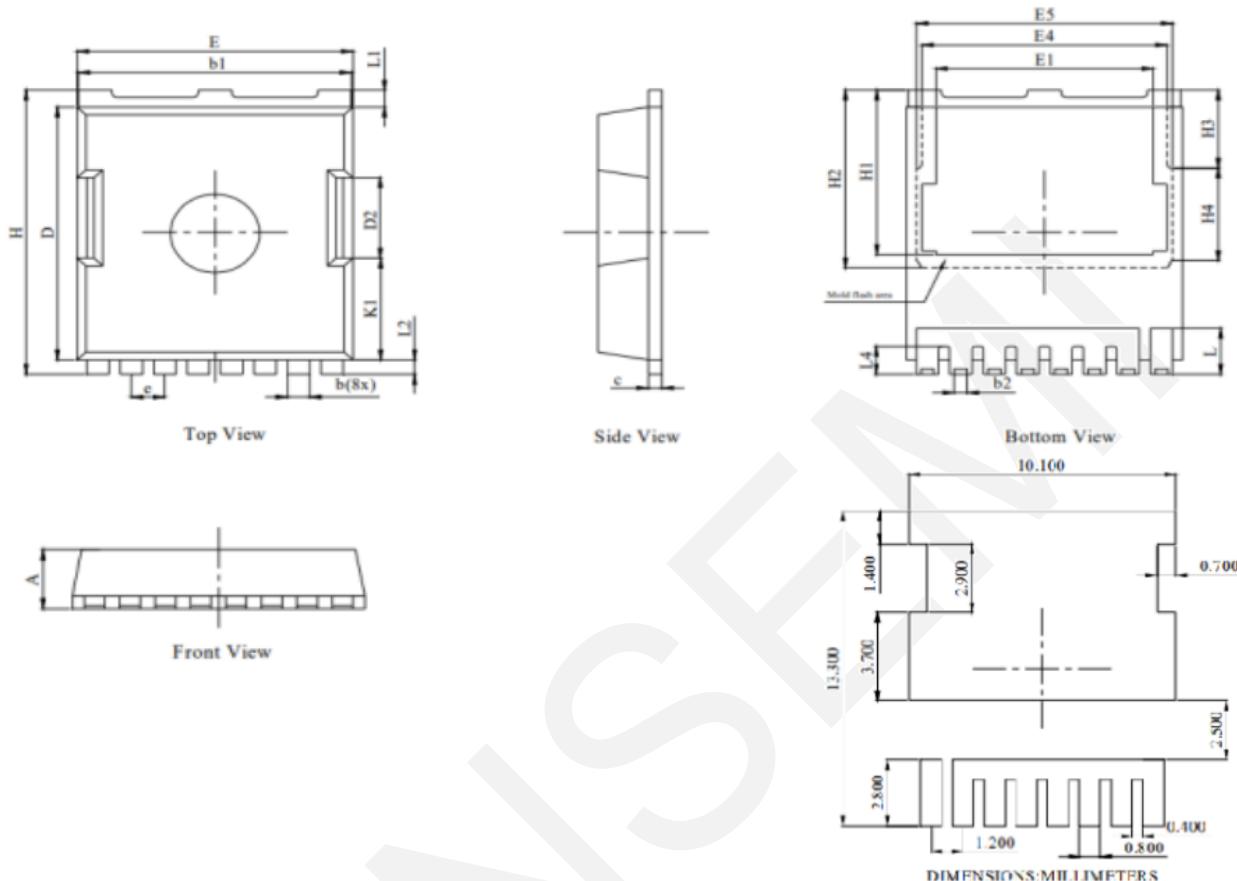
Normalized Threshold Voltage vs.
Junction Temperature



Normalized Maximum Transient Thermal Impedance



8.Package Dimensions



DIM.	MILLIMETER		
	MIN	NOM	MAX
A	2.20	2.30	2.50
b	0.70	0.80	0.90
b1	9.70	9.80	9.90
b2	0.42	0.46	0.50
C	0.40	0.50	0.65
D	10.28	10.38	10.58
D2		3.30	
E	9.70	9.90	10.10
E1		7.80	
E4		8.80	
E5		9.20	
e	1.20(BSC)		
H	11.48	11.68	11.88
H1	6.55	6.75	6.85
H2		7.30	
H3		3.20	
H4		3.80	
K1		4.18	
L	1.70	1.90	2.10
L1		0.70	
L2		0.60	
L4	1.00	1.15	1.30

9. Important Notice

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